Notice of References Cited Application/Control No. 10/772,292 Examiner SIMON D. NGUYEN Applicant(s)/Patent Under Reexamination LEE ET AL. Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-2004/0087292	05-2004	Shiu et al.	455/232.1
*	В	US-6,862,439	03-2005	Feng, Shen	455/234.1
*	С	US-2003/0064696	04-2003	Akamine et al.	455/311
*	D	US-2002/0151289	10-2002	Rahman et al.	455/232.1
*	Е	US-6,442,380	08-2002	Mohindra, Rishi	455/234.1
*	F	US-6,321,073	11-2001	Luz et al.	455/239.1
*	G	US-2003/0174079	09-2003	Soltanian et al.	341/118
*	Н	US-6,996,383	02-2006	Hughes et al.	455/138
*	1	US-6,748,200	06-2004	Webster et al.	455/234.1
*	J	US-2003/0119464	06-2003	Toyoda et al.	455/245.1
*	К	US-2002/0160734	10-2002	Li et al.	455/245.1
*	L	US-2004/0152432	08-2004	Gu, Qizheng	455/136
*	М	US-2004/0203472	10-2004	Chien, Charles	455/068

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Q					
	R					
	S					
	Т					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	ט	
	>	
	>	
	x	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.